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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Attorney Docket No. 01-801-C)

In re Application of:)
)
William Cork et al.) Examiner: To Be Assigned
)
Serial No. 10/757,780) Group Art Unit: 1637
)
Filed: January 15, 2004) Confirmation No.: 5427
)
For: Nanoparticle Imaging System and Method)

TRANSMITTAL LETTER

Mail Stop: Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In regard to the above identified application.

1. We are transmitting herewith the attached:
 - a) Second Supplemental Information Disclosure Statement – U.S. PTO Form 1449;
 - b) Copies of four (4) references (2-5);
 - c) Copy of Supplementary European Search Report dated November 8, 2005; and
 - d) Return Postcard.
2. With respect to fees:
 - a) No fee is due.
 - b) Please charge any underpayment or credit any overpayment to our Deposit Account No. 13-2490. A duplicate copy of this sheet is enclosed.
3. CERTIFICATE OF MAILING UNDER 37 CFR § 1.8: The undersigned hereby certifies that this Transmittal Letter and the papers, as described in paragraph 1 hereinabove, are being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to the Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on December 6, 2005.

Respectfully submitted,

David L. Ciesielski
David L. Ciesielski
Registration No. 57,432

FORM PTO-1449
(Rev. 2-32)

U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No.

01-801-C

Serial No.

10/757,780

**SECOND SUPPLEMENTAL
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Use several sheets if necessary)



Applicant:
William Cork et al.

Filing Date:
January 15, 2004

Group:
1637

U.S. PATENT DOCUMENTS

| Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date if Appropriate |
|------------------|----|-----------------|-----------|--------|-------|----------|----------------------------|
| | 1. | 6,248,988 | 6-19-2001 | Krantz | 250 | 201.3 | 5-5-1998 |
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FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|-----------|---------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | 2. | WO 99/13319 | 3-18-1999 | PCT | G01N | 21/55 | | |
| | 3. | WO 98/44330 | 10-8-1998 | PCT | G01N | | | |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc).

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|-----------------|--|
| 4. | Brown, C.S., et al., "Image metrics in the statistical analysis of DNA microarray data," Proceedings of the National Academy of Sciences of USA, National Academy of Science, Washington D.C., US, Vol. 98, No. 16, July 31, 2001, pgs. 8944-8949. |
| 5. | Takahagi, T., et al., "Scanning Electron Microscope Observation of Heterogeneous Three-Dimensional Nanoparticle Arrays Using DNA," Japanese Journal of Applied Physics, Japan Society of Applied Physics, Tokyo, Japan, Vol. 40, No. 5B, Part 2, May 15, 2001, pgs. L521-L523. |
| EXAMINER | |
| DATE CONSIDERED | |

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.